DW OR NT PACKAGE

(TOP VIEW)

SDAS237A - OCTOBER 1984 - REVISED JANUARY 1995

- 3-State I/O-Type Read-Back Inputs
- Bus-Structured Pinout
- True Logic Outputs
- Package Options Include Plastic Small-Outline (DW) Packages and Standard Plastic (NT) 300-mil DIPs

description

This 10-bit latch is designed specifically for storing the contents of the input data bus and providing the capability of reading back the stored data onto the input data bus.

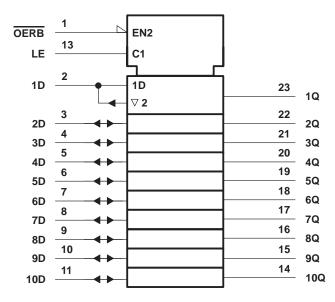
The ten latches are transparent D-type latches. While the latch-enable (LE) input is high, the Q outputs follow the data (D) inputs.

OERB 24 VCC 1D 23 1Q 2 2D ∏3 22 ∏ 2Q 21 T 3Q 3D | 4 4D 15 20**∏** 4Q 5D ∏6 6D 18 **∏** 6Q 7D 18 17**∏** 7Q 8D **1**9 16 8Q 15 9Q 9D [] 10 14**∏** 10Q 10D **∏**11 GND 112 13 | LE

Read back is provided through the output-enable (\overline{OERB}) input. When \overline{OERB} is taken low, the data present at the output of the data latches passes back onto the input data bus. When \overline{OERB} is taken high, the output of the data latches is isolated from the D inputs. \overline{OERB} does not affect the internal operation of the latches; however, precautions should be taken to avoid a bus conflict.

The SN74ALS994 is characterized for operation from 0°C to 70°C.

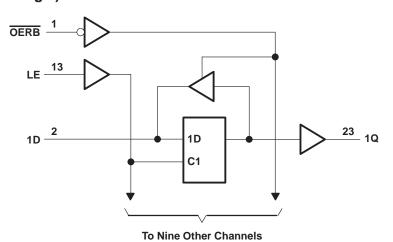
logic symbol†



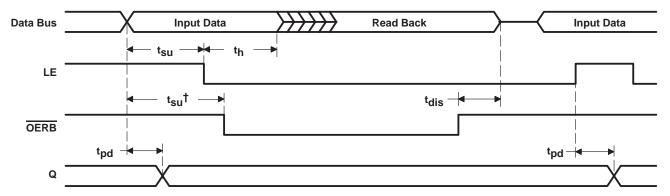
† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



logic diagram (positive logic)



timing diagram



[†] This setup time ensures that the read-back circuit will not create a conflict on the input data bus.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, V _{CC}	7 V
Input voltage, V _I (OERB and LE)	7 V
Voltage applied to D inputs	5.5 V
Operating free-air temperature range, T _A	0°C to 70°C
Storage temperature range	65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

SDAS237A - OCTOBER 1984 - REVISED JANUARY 1995

recommended operating conditions

			MIN	NOM	MAX	UNIT	
VCC	Supply voltage			5	5.5	V	
VIH	High-level input voltage		2			V	
V _{IL}	Low-level input voltage	ut voltage			0.8	V	
la	High-level output current	Q			-2.6	mA	
ЮН		D			-0.4		
lOL	Low-level output current	Q			24	mA	
		D			8		
t _W	Pulse duration, LE high					ns	
	Setup time	Data before LE↓	10			no	
t _{su}		Data before OERB↓†	10			ns	
t _h	Hold time, data after LE↓		5			ns	
TA	Operating free-air temperature		0		70	°C	

[†] This setup time ensures that the read-back circuit will not create a conflict on the input data bus.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER TEST CONDITIONS		М	IN TYP‡	MAX	UNIT		
٧ıK		V _{CC} = 4.5 V,	I _I = -18 mA			-1.2	V	
Vон	All outputs	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	VCC	; –2			
	Q	V _{CC} = 4.5 V,	$I_{OH} = -2.6 \text{ mA}$	2	.4 3.2		V	
VOL	D V _{CC} = 4.5 V	V00 - 45 V	I _{OL} = 4 mA		0.25	0.4		
		$I_{OL} = 8 \text{ mA}$		0.35	0.5	V		
	Q V _{CC} = 4.5 V	I _{OL} = 12 mA		0.25	0.4			
		vCC = 4.5 v	I _{OL} = 24 mA		0.35	0.5		
II	OERB, LE	V _{CC} = 5.5 V	V _I = 7 V			0.1	mA	
	D inputs		V _I = 5.5 V			0.1		
ΊΗ	OERB, LE	V: 0.7.V			20			
	D inputs§	$V_{CC} = 5.5 V$	V _I = 2.7 V			20	μΑ	
I _{IL}	OERB, LE	V _{CC} = 5.5 V,	V- 0.4 V			-0.1	mA	
	D inputs§		V _I = 0.4 V			-0.1		
IOI		V _{CC} = 5.5 V,	V _O = 2.25 V	_;	30	-112	mA	
ICC	<u>V_{CC} =</u> 5.5 V, OERB high		Q outputs high		30	50	mA	
		OERB high	Q outputs low		52	82	IIIA	

[‡] All typical values are at V_{CC} = 5 V, T_A = 25°C. § For I/O ports (Q_A thru Q_H), the parameters I_{IH} and I_{IL} include the off-state output current. ¶ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I_{OS}.

SN74ALS994 10-BIT D-TYPE TRANSPARENT READ-BACK LATCH

SDAS237A - OCTOBER 1984 - REVISED JANUARY 1995

switching characteristics (see Figure 1)

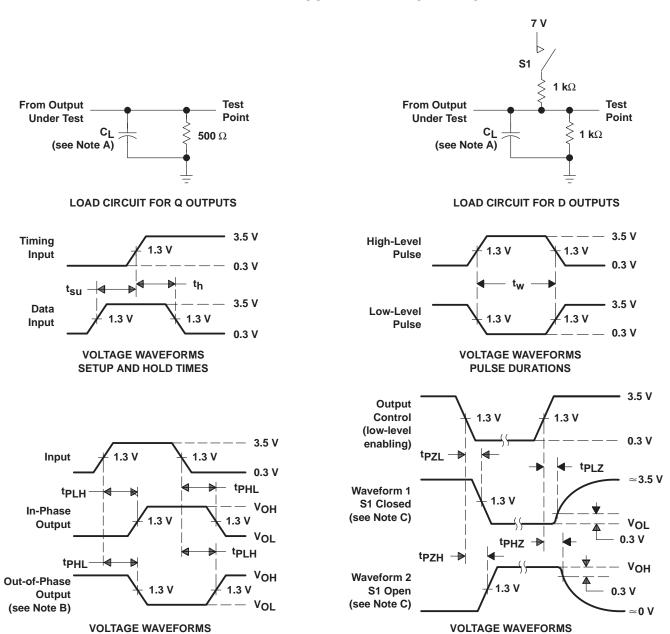
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 4.5 C _L = 50 pF T _A = MIN to	UNIT	
			MIN	MAX	
tPLH	D		3	14	
^t PHL		Q	4	18	ns
^t PLH	LE		6	21	ne
t _{PHL}		Q	8	27	ns
t _{en} ‡	OERB	D	4	21	20
t _{dis} §			2	16	ns

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

t_{en} = t_{PZH} or t_{PZL} t_{dis} = t_{PHZ} or t_{PLZ}

ENABLE AND DISABLE TIMES, 3-STATE OUTPUTS

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

PROPAGATION DELAY TIMES

- B. When measuring propagation delay times of 3-state outputs, switch S1 is open.
- C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- D. All input pulses have the following characteristics: PRR \leq 1 MHz, $t_f = t_f = 2$ ns, duty cycle = 50%.

Figure 1. Load Circuits and Voltage Waveforms

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